

Supporting Information

A novel single-composition trichromatic white-emitting $\text{Sr}_{3.5}\text{Y}_{6.5}\text{O}_2(\text{PO}_4)_{1.5}(\text{SiO}_4)_{4.5}:\text{Ce}^{3+}/\text{Tb}^{3+}/\text{Mn}^{2+}$ phosphor: synthesis, luminescent properties and applications for white LEDs

Haikun Liu^a, Yi Luo^a, Zhiyong Mao^b, Libing Liao^{*,a}, Zhiguo Xia^{*,a}

^a*School of Materials Science and Technology, China University of Geosciences, Beijing 100083, China*

^b*Shanghai Institute of Ceramics, Chinese Academy of Sciences, Shanghai, China*

Table S1. Crystallographic Data for $\text{Sr}_{3.5}\text{Y}_{6.5}\text{O}_2(\text{PO}_4)_{1.5}(\text{SiO}_4)_{4.5}$ Based on Rietveld

Refinement.

Formula	$\text{Sr}_{3.5}\text{Y}_{6.5}\text{O}_2(\text{PO}_4)_{1.5}(\text{SiO}_4)_{4.5}$
Space group	P63/m
Cell parameters	$a = b = 9.4418(13) \text{ \AA}$, $c = 6.8992(9) \text{ \AA}$ $\alpha = 90^\circ$, $\beta = 90^\circ$, $\gamma = 120^\circ$ $V = 529.27(16) \text{ \AA}^3$, $Z = 1$ R - Bragg = 5.74
Reliability factors	$R_{\text{exp}} = 4.56\%$ $R_{\text{wp}} = 9.63\%$ $R_p = 6.32\%$ $GOF = 2.11$

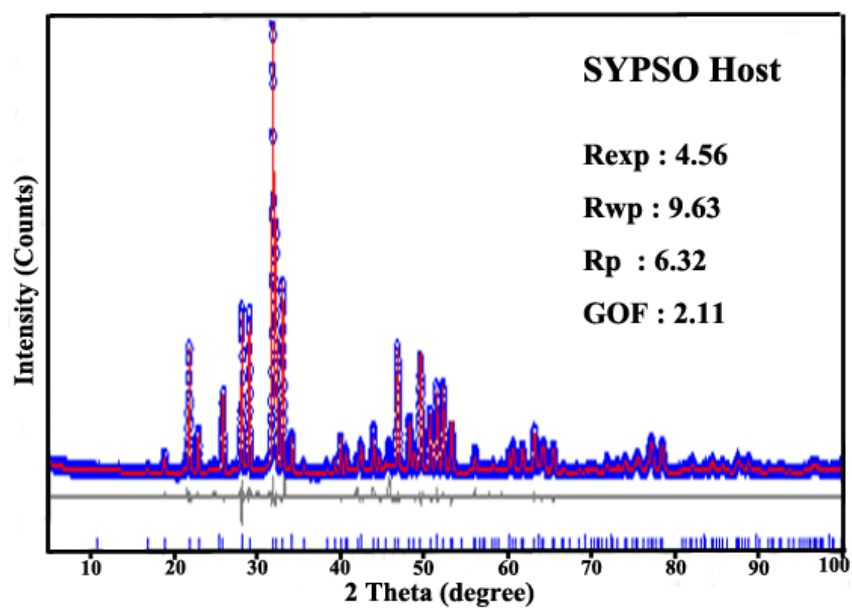


Figure S1. Rietveld refinement XRD patterns of SYPSO Compound at room temperature by TOPAS program. (Solid red lines are calculated intensities, and circles are the observed intensities. Short vertical lines show the position of Bragg reflections of the calculated pattern. Gray solid lines below the profiles stand for the difference between the observed and the calculated intensities.

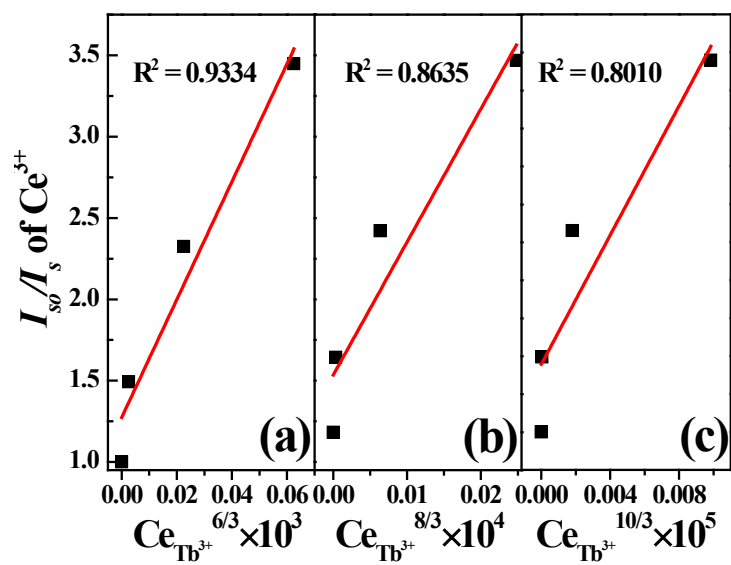


Figure S2. Dependence of I_{S0}/I_S of Ce^{3+} on (a) $C^{6/3}$, (b) $C^{8/3}$, and (c) $C^{10/3}$.

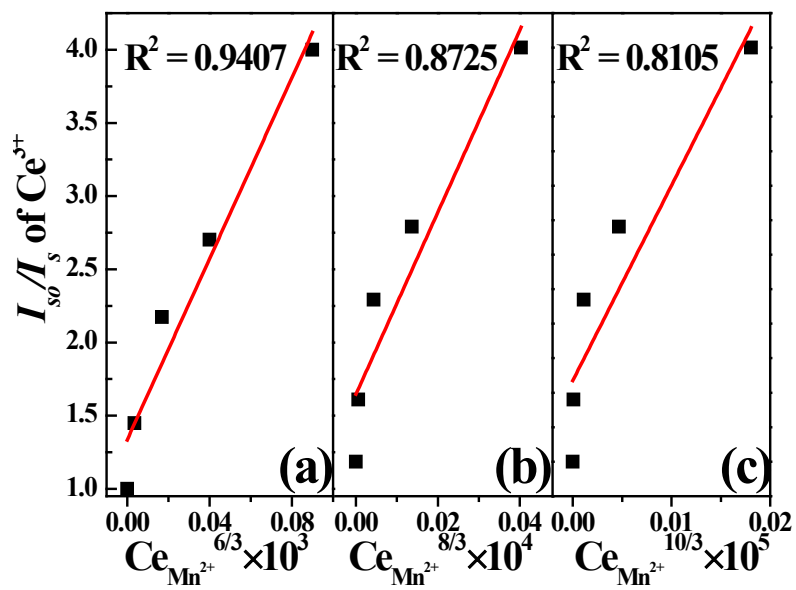


Figure S3. Dependence of I_{S0}/I_S of Ce^{3+} on (a) $C^{6/3}$, (b) $C^{8/3}$, and (c) $C^{10/3}$.